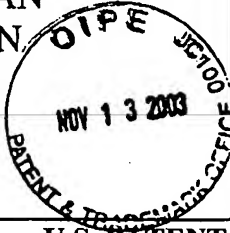


INFORMATION DISCLOSURE CITATION IN AN APPLICATION				ATTY. DOCKET NO. 57454-963		SERIAL NO. Divisional of Serial No. 09/903,735 10/633576	
(PTO-1449)				APPLICANT Hiroshi MAEDA, ET AL.			
FILING DATE August 5, 2003				GROUP To be assigned			



U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
TT	6,424,011	07/2002	Assaderaghi et al	257	350	
TT	6,255,151	07/2001	Fukuda et al	257	296	

FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
TT	M. Igarashi, A. Harada, H. Amishiro, H. Kawashima, N. Morimoto, Y. Kusumi, T. Saito, A. Ohsaki, T. Mori, T. Fukada, Y. Toyoda, K. Higashitani, and H. Arima, "The Best Combination Of Aluminum and Copper Interconnects For a High Performance 0.18μm CMOS Logic Device," IEDM98, 1998, PP. 829-832.
TT	J. Heidenreich, D. Edelstein, R. Goldblatt, W. Cote, C. Uzoh, N. Lustig, T. McDevitt, A. Stamper, A. Simon, J. Dukovic, R. Wachnik, H. Rathore, S. Luce, and J. Slattery, "Copper Dual <u>Damascene</u> Wiring for Sub-0.25μm CMOS Technology," PP. 13-15.

EXAMINER <div style="text-align: center; font-family: cursive; font-size: 1.2em;"> thien kmc </div>	DATE CONSIDERED <div style="text-align: center; font-family: cursive; font-size: 1.2em;"> 09/03/04 </div>
--	--

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

INFORMATION DISCLOSURE CITATION IN AN APPLICATION

 ATTY. DOCKET NO.
57454-963

 SERIAL NO.
10/633,576

 APPLICANT
Hiroshi Maeda, et al.

 FILING DATE
August 05, 2003

 GROUP
2811

(PTO-1449)

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code(s) (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			
		US			

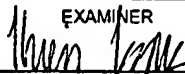
FOREIGN PATENT DOCUMENTS

EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes - Number - Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation	
						Yes	No
TT		1999-0062885	07/26/1999				X

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.

EXAMINER



DATE CONSIDERED

09/03/04

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

 C1825
to 16
cler